#### SN74F2373 25-Ω OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS SDF\$100 - JANUARY 1996

<ul> <li>Eight Latches in a Single Package</li> <li>3-State True Outputs With 25-Ω Sink</li> </ul>	DB, DW, OR N PACKAGE (TOP VIEW)					
Resistors						
Full Parallel Access for Loading	OE 1 20 V <sub>CC</sub> 1Q 2 19 8Q					
<ul> <li>Buffered Control Inputs</li> </ul>	1D 3 18 8D					
Package Options Include Plastic	2D 🛛 4 17 🗍 7D					
Small-Outline (DW), Shrink Small-Outline	2Q 🛛 5 🛛 16 🕽 7Q					
(DB) Packages, and Plastic (N) DIPs	3Q <b>[</b> 6 15 <b>]</b> 6Q					
	3D 🛛 7 14 🗍 6D					
description	4D 🛛 8 13 🗍 5D					
This 8-bit latch features 3-state outputs designed to sink up to 12 mA, and include 25- $\Omega$ sink resitors	4Q [] 9 12 ] 5Q GND [] 10 11 ] LE					

The eight latches of the SN74F2373 are transparent D-type latches. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When the LE is taken low, the Q outputs are latched at the logic levels set up at the D inputs.

A buffered output-enable ( $\overline{OE}$ ) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

OE input does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN74F373 is available in TI's shrink small-outline package (DB), which provides the same I/O pin count and functionality of standard small-outline packages in less than half the printed-circuit-board area.

The SN74F373 is characterized for operation from 0°C to 70°C.

to reduce overshoot and undershoot.

FUNCTION TABLE (each latch)						
INPUTS			OUTPUT			
OE	LE	D	Q			
L	Н	Н	Н			
L	Н	L	L			
L	L	Х	Q <sub>0</sub>			
н	Х	Х	Z			



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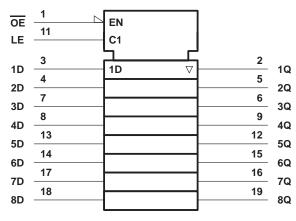
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



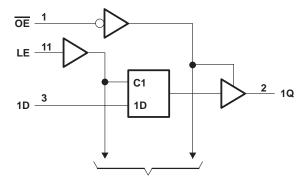
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# logic symbol<sup>†</sup>



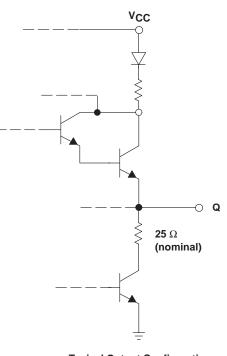
# logic diagram (positive logic)



**To Seven Other Channels** 

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

# schematic diagram



**Typical Output Configuration** 



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, $V_{CC}$
Input voltage range, V <sub>I</sub> (see Note 1)
Input current range, I <sub>1</sub>
Voltage range applied to any output in the disabled or power-off state, $V_O$
Voltage range applied to any output in the high state, $V_O$
Current into any output in the low state, IO
Operating free-air temperature range, T <sub>A</sub> 0°C to 70°C
Storage temperature range, T <sub>stg</sub>
<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and
functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not

implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded if the input current ratings are observed.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
IIK	Input clamp current			-18	mA
ЮН	High-level output current			- 3	mA
IOL	Low-level output current			12	mA
ТА	Operating free-air temperature	0		70	°C

#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			TYP <sup>‡</sup>	MAX	UNIT		
VIK	V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA			-1.2	V		
	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = – 1 mA	2.5	3.4				
VOH	VCC = 4.5 V	$I_{OH} = -3 \text{ mA}$	2.4	3.3	V			
	V <sub>CC</sub> = 4.75 V,	$I_{OH} = -1 \text{ mA to} - 3 \text{ mA}$	2.7					
Vai		I <sub>OL</sub> = 1 mA		0.2	0.5	V		
		I <sub>OL</sub> = 12 mA		0.5	0.75	v		
IOZ(H)	V <sub>CC</sub> = 5.5 V,	$V_{O} = 2.7 V$			50	μΑ		
IOZ(L)	V <sub>CC</sub> = 5.5 V,	$V_{O} = 0.5 V$			-50	μΑ		
l	V <sub>CC</sub> = 5.5 V,	$V_{I} = 7 V$			0.1	mA		
Ιн	V <sub>CC</sub> = 5.5 V,	VI = 2.7 V			20	μΑ		
١ <sub>IL</sub>	V <sub>CC</sub> = 5.5 V,	VI = 0.5 V			- 0.6	mA		
IOS§	V <sub>CC</sub> = 5.5 V,	$V_{O} = 0$	-60		-150	mA		
ICC(H)	V <sub>CC</sub> = 5.5 V,	See Note 2, Condition A		38	55	mA		
ICC(L)	V <sub>CC</sub> = 5.5 V,	See Note 2, Condition B		46	66	mA		
ICC(Z)	V <sub>CC</sub> = 5.5 V, See Note 2, Condition C			43	62	mA		

<sup>‡</sup> All typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25^{\circ}C$ .

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. NOTE 2:

 $I_{CC}$  is measured with the outputs open under the following conditions:

A. OE at ground (0) and all other inputs at 4.5 V.

B. LE at 4.5 V and all other inputs grounded.
C. OE at 4.5 V and all other inputs grounded.



## SN74F2373 25-Ω OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS SDFS100 – JANUARY 1996

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

		V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C		MIN	МАХ	UNIT
		MIN	MAX			
tw	Pulse duration, LE high	6		6		ns
t <sub>su</sub>	Setup time, data before LE $\downarrow$	2		2		ns
th	Hold time, data after LE $\downarrow$	5		6		ns

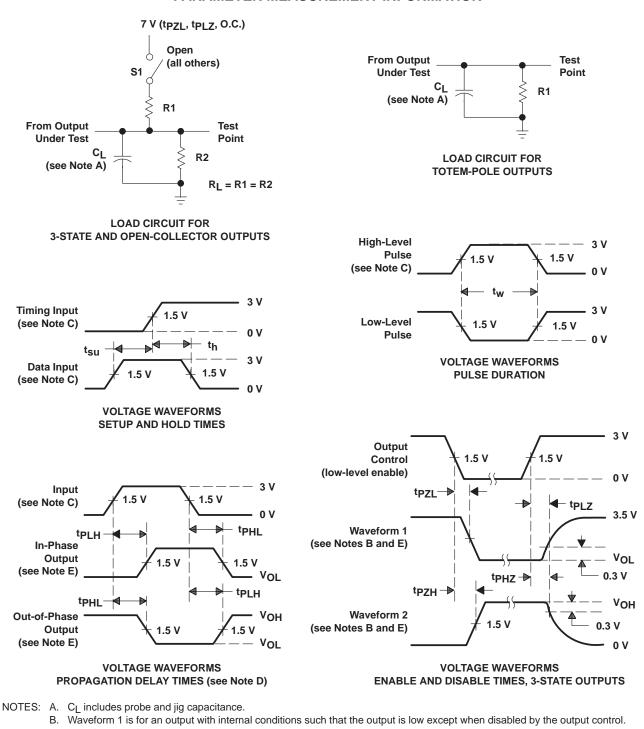
# switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	$\begin{array}{c c} V_{CC} = 5 \ V, & V_{CC} = 4.5 \ V \ TO \ 5.5 \ V, \ C_L \\ C_L = 50 \ PF, & = 50 \ PF, \\ (OUTPUT) & R_1 = 500 \ \Omega, & R_1 = 500 \ \Omega, \\ R_2 = 500 \ \Omega, & R_2 = 500 \ \Omega, \\ T_A = 25^{\circ}C & T_A = MIN \ TO \ MAX^{\dagger} \end{array}$			C <sub>L</sub> = 50 PF, R <sub>1</sub> = 500 Ω, R <sub>2</sub> = 500 Ω,		UNIT	
			MIN	TYP	MAX	MIN	MAX	
<sup>t</sup> PLH	D	0	2.2	4.4	7	2.1	9	ns
<sup>t</sup> PHL		Q	1.2	4.1	5.5	1.2	7	115
<sup>t</sup> PLH	LE	0	4.2	7.3	11.5	4.2	13	ns
<sup>t</sup> PHL		Q	2.2	4.2	7	2.2	8	115
<sup>t</sup> PZH	OE	Q	1.2	4.1	11	1.2	12	ns
tPZL		3	1.2	6	8.3	1.2	9.5	115
<sup>t</sup> PHZ	OE	Q	1.2	4.2	6.5	1.2	7.5	200
tPLZ		y y	1.2	3.5	6	1.2	6	ns

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



#### SN74F2373 25-Ω OCTAL TRANSPARENT D-TYPE LATCH WITH 3-STATE OUTPUTS SDFS100 - JANUARY 1996



#### PARAMETER MEASUREMENT INFORMATION

- Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\le 1$  MHz, t<sub>r</sub> = t<sub>f</sub>  $\le 2.5$  ns, duty cycle = 50%.
- D. When measuring propagation delay times of 3-state outputs, switch S1 is open. Ε.
  - The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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